

## Specification Sheet

**CIGT201210UHR47MNE (2012 / EIA 0805)**



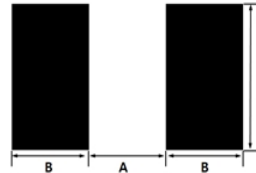
### APPLICATION

Smart phones, Tablet, Wearable devices, Power converter modules, etc.

### FEATURES

Small power inductor for mobile devices  
Low DCR structure and high efficiency inductor for power circuits.  
Monolithic structure for high reliability  
Free of all RoHS-regulated substances  
Halogen free

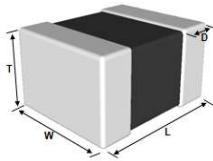
### RECOMMENDED LAND PATTERN



Unit : mm

TYPE	2012
A	0.8
B	0.8
C	1.3

### DIMENSION



TYPE	Dimension [mm]			
	L	W	T	D
2012	2.0±0.2	1.25±0.2	1.0 max	0.5±0.2

### DESCRIPTION

Part no.	Size [inch/mm]	Thickness [mm] (max)	Inductance [uH]	Inductance tolerance (%)	DC Resistance [mΩ]		Rated DC Current (Isat) [A]		Rated DC Current (Irms) [A]	
					Max.	Typ.	Max.	Typ.	Max.	Typ.
CIGT201210UHR47MNE	0805/2012	1.0	0.47	±20	31	25	4.9	5.4	3.6	4.1

- \* Inductance : Measured with a LCR meter 4991A(Agilent) or equivalent (Test Freq. 1MHz, Level 0.1V)
- \* DC Resistance : Measured with a Resistance HI-TESTER 3541(HIOKI) or equivalent
- \* Maximum allowable DC current : Value defined when DC current flows and the initial value of inductance has decreased by 30% or when current flows and temperature has risen to 40°C whichever is smaller. (Reference: ambient temperature is 25°C±10)
- (Isat) : Allowable current in DC saturation : The DC saturation allowable current value is specified when the decrease of the initial inductance value at 30% (Reference: ambient temperature is 25°C±10)
- (Irms) : Allowable current of temperature rise : The temperature rise allowable current value is specified when temperature of the inductor is raised 40°C by DC current. (Reference: ambient temperature is 25°C±10)
- \* Absolute maximum voltage : Absolute maximum voltage DC 20V.
- \* Operating temperature range : -40 to +125°C (Including self-temperature rise)

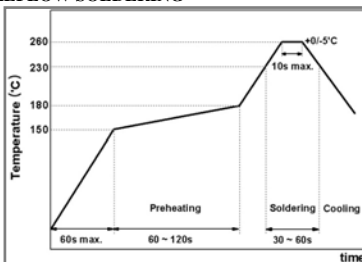
### PRODUCT IDENTIFICATION

**CIG    I    2012    10    UH    R47    M    N    E**  
**(1)    (2)    (3)    (4)    (5)    (6)    (7)    (8)    (9)**

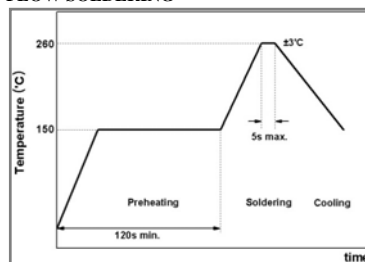
- (1) Power Inductor
- (2) Type (T: Metal Composite Thin Film Type)
- (3) Dimension (2012: 2.0mm × 1.25mm)
- (4) Thickness (10: 1.0mm)
- (5) Remark (Characterization Code)
- (6) Inductance (R47: 0.47 uH)
- (7) Toleranc (M:±20%)
- (8) Internal Code
- (9) Packaging (C:paper tape, E:embossed tape)

### RECOMMENDED SOLDERING CONDITION

#### REFLOW SOLDERING



#### FLOW SOLDERING



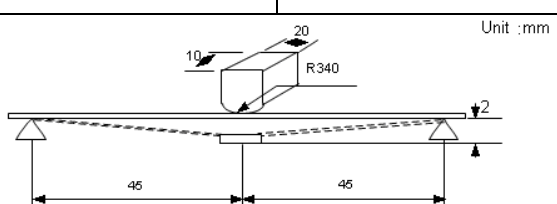
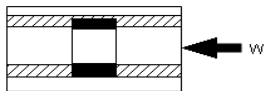
#### IRON SOLDERING

Temperature of Soldering Iron Tip	280 °C max.
Preheating Temperature	150 °C min.
Temperature Differential	ΔT ≤ 130 °C
Soldering Time	3sec max.
Wattage	50W max.

### PACKAGING

Packaging Style	Quantity(pcs/reel)
Embossed Taping	3000 pcs

## Reliability Test

Item	Specified Value	Test Condition	
Solderability	More than 90% of terminal electrode should be soldered newly.	After being dipped in flux for 4±1 seconds, and preheated at 150 ~ 180 °C for 2 ~ 3 min, the specimen shall be immersed in solder at 245±5 °C for 4±1 seconds.	
Resistance to Soldering	No mechanical damage. Remaining terminal Electrode: 75% min. Inductance change to be within ±20% to the initial.	After being dipped in flux for 4±1 seconds, and preheated at 150 ~ 180 °C for 2 ~ 3 min, the specimen shall be immersed in solder at 260±5 °C for 10 ±0.5 seconds.	
Thermal Shock (Temperature Cycle test)	No mechanical damage Inductance change to be within ±20% to the initial.	Repeat 100 cycles under the following conditions. -40±3 °C for 30 min → 85±3 °C for 30 min	
High Temp. Humidity Resistance Test	No mechanical damage Inductance change to be within ±20% to the initial	85±2 °C, 85%RH, for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.	
Low Temperature Test	No mechanical damage Inductance change to be within ±20% to the initial.	Solder the sample on PCB. Exposure at -55±2 °C for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24hours.	
High Temperature Test	No mechanical damage Inductance change to be within ±20% to the initial.	Solder the sample on PCB. Exposure at 125±2 °C for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24hours.	
High Temp. Humidity Resistance Loading Test	No mechanical damage Inductance change to be within ±20% to the initial	85±2 °C, 85%RH, Rated Current for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.	
High Temperature Loading Test	No mechanical damage Inductance change to be within ±20% to the initial	85±2 °C, Rated Current for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.	
Reflow Test	No mechanical damage Inductance change to be within ±20% to the initial	Peak 260±5 °C, 3 times	
Vibration Test	No mechanical damage Inductance change to be within ±20% to the initial.	Solder the sample on PCB. Vibrate as apply 10~55Hz, 1.5mm amplitude for 2 hours in each of three(X,Y,Z) axis (total 6 hours).	
Bending Test	No mechanical damage	Bending Limit; 2mm Test Speed; 1.0mm/sec. Keep the test board at the limit point in 5 sec. PCB thickness : 1.6mm	
			
Terminal Adhesion Test	No indication of peeling shall occur on the terminal electrode.	W(kgf)	TIME(sec)
		0.5	10±1
			
Drop Test	No mechanical damage Inductance change to be within ±20% to the initial.	Random Free Fall test on concrete plate. 1 meter, 10 drops	
Ipeak (AC+DC Load Life)	No mechanical damage Inductance change to be within ±20% to the initial	85±2 °C, 85%RH, Load(Ipeak) for 120 hours. (Frequency:1MHz, Load(Ipeak):1.5hr on / 0.5hr off) Measure the test items after leaving at normal temperature and humidity for 24 hours. * Load(Ipeak) = Irms(max)×1.4	

### 1. Model : CIGT201210UHR47MNE

### 2. Description

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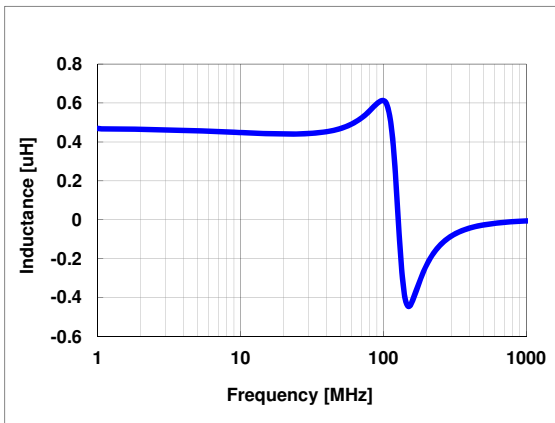
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### 3. Characteristics data

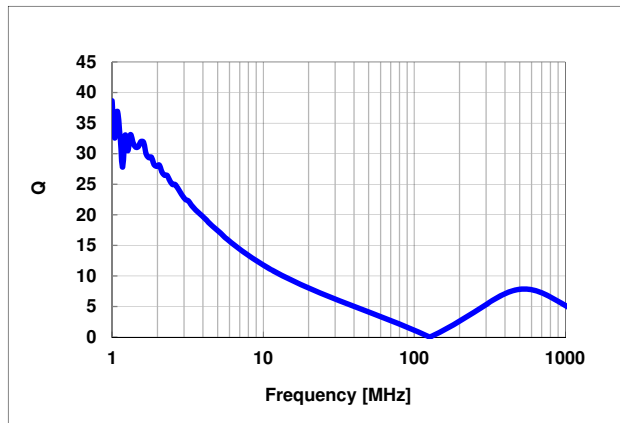
#### 1) Frequency characteristics (Ls)

Agilent E4294A +E4991A , 1MHz to 1,000MHz

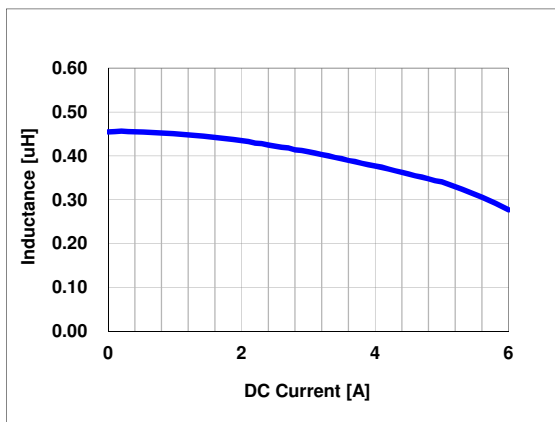


#### 2) Frequency characteristics (Q)

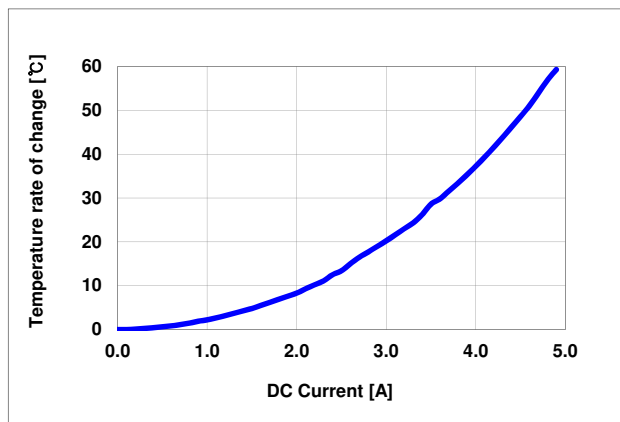
Agilent E4294A +E4991A , 1MHz to 1,000MHz



#### 3) DC Bias characteristics (Typ.)



#### 4) Temperature characteristics (Typ.)



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The data sheets include the typical data for design reference only. If there is any question regarding the data sheets, please contact our sales personnel or application engineers